

CMOS 4-Bit Magnitude Comparator

High Voltage Types (20-Volt Rating)

■ CD4585B is a 4-bit magnitude comparator designed for use in computer and logic applications that require the comparison of two 4-bit words. This logic circuit determines whether one 4-bit word (Binary or BCD) is "less than", "equal to", or "greater than" a second 4-bit word.

The CD4585B has eight comparing inputs (A3, B3, through A0, B0), three outputs (A < B, A = B, A > B) and three cascading inputs (A < B, A = B, A > B) that permit systems designers to expand the comparator function to 8, 12, 16.....4N bits. When a single CD4585B is used, the cascading inputs are connected as follows: (A < B) = low, (A = B) = high, (A > B) = high.

Cascading these units for comparison of more than 4 bits is accomplished as shown in Fig. 13.

The CD4585B types are supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix). This device is pin-compatible with low-power TTL type 7485 and the CMOS types MC14585 and 40085.

Features:

- Expansion to 8,12,16.....4N bits by cascading units
- Medium-speed operation: compares two 4-bit words in 180 ns (typ.) at 10 V
- 100% tested for quiescent current at 20 V
- Standardized symmetrical output characteristics
- 5-V, 10-V, and 15-V parametric ratings
- Maximum input current of 1 μ A at 18 V over full package-temperature range; 100 nA at 18 V and 25°C
- Noise margin (full package temperature range) = 1 V at $V_{DD} = 5$ V
2 V at $V_{DD} = 10$ V
2.5 V at $V_{DD} = 15$ V
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

Applications:

- Servo motor controls
- Process controllers

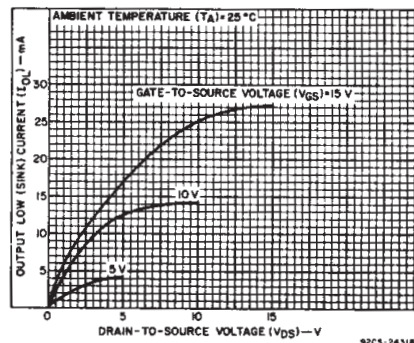
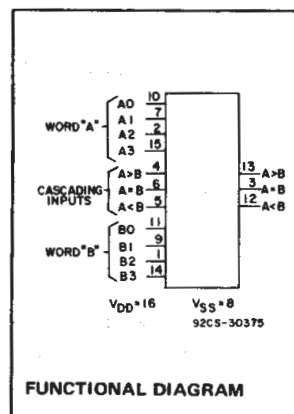


Fig. 1 - Typical output low (sink) current characteristics.

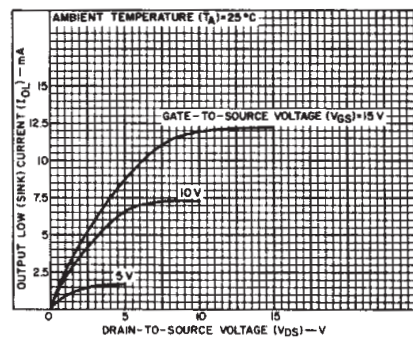


Fig. 2 - Minimum output low (sink) current characteristics.

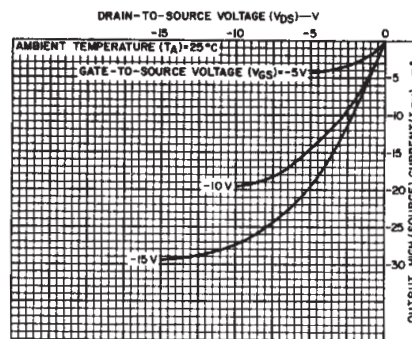


Fig. 3 - Typical output high (source) current characteristics.

MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE RANGE, (V_{DD})

Voltages referenced to V_{SS} Terminal -0.5V to +20V

INPUT VOLTAGE RANGE, ALL INPUTS -0.5V to $V_{DD} + 0.5$ V

DC INPUT CURRENT, ANY ONE INPUT ± 10 mA

POWER DISSIPATION PER PACKAGE (P_D):

For $T_A = -55^\circ\text{C}$ to $+100^\circ\text{C}$ 500mW

For $T_A = +100^\circ\text{C}$ to $+125^\circ\text{C}$ Derate Linearly at 12mW/ $^\circ\text{C}$ to 200mW

DEVICE DISSIPATION PER OUTPUT TRANSISTOR

FOR $T_A = \text{FULL PACKAGE-TEMPERATURE RANGE (All Package Types)}$ 100mW

OPERATING-TEMPERATURE RANGE (T_A) -55°C to $+125^\circ\text{C}$

STORAGE TEMPERATURE RANGE (T_{stg}) -65°C to $+150^\circ\text{C}$

LEAD TEMPERATURE (DURING SOLDERING):

At distance $1/16 \pm 1/32$ inch (1.59 ± 0.79 mm) from case for 10s max $+265^\circ\text{C}$

RECOMMENDED OPERATING CONDITIONS

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	LIMITS		UNITS
	Min.	Max.	
Supply-Voltage Range (For $T_A = \text{Full Package-Temperature Range}$)	3	18	V

CD4585B Types

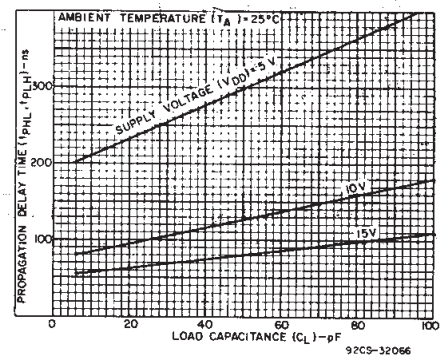
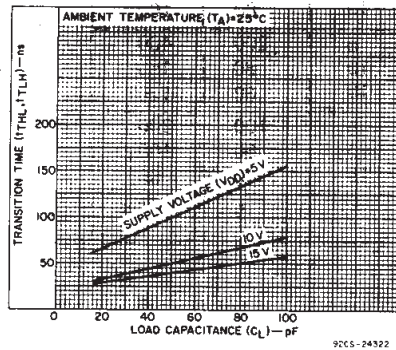
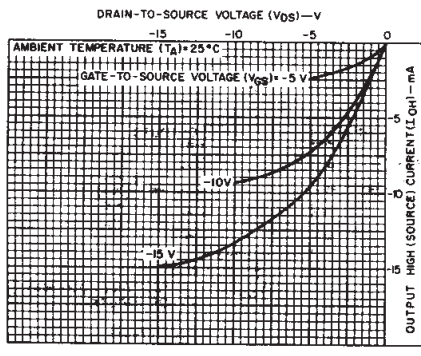
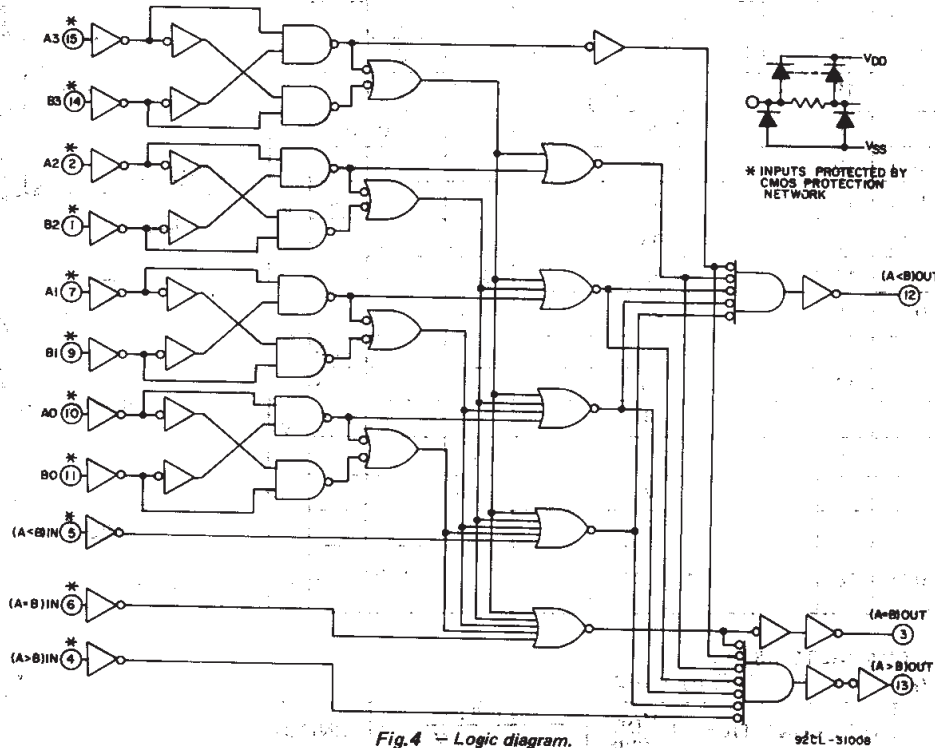
TRUTH TABLE

INPUTS				CASCADING			OUTPUTS		
COMPARING			CASCADING			A < B	A = B	A > B	
A3, B3	A2, B2	A1, B1	A0, B0	A < B	A = B	A > B	A < B	A = B	A > B
A3 > B3	X	X	X	X	X	1	0	0	1
A3 = B3	A2 > B2	X	X	X	X	1	0	0	1
A3 = B3	A2 = B2	A1 > B1	X	X	X	1	0	0	1
A3 = B3	A2 = B2	A1 = B1	A0 > B0	X	X	1	0	0	1
A3 = B3	A2 = B2	A1 = B1	A0 = B0	0	0	1	0	0	1
A3 = B3	A2 = B2	A1 = B1	A0 = B0	0	1	X	0	1	0
A3 = B3	A2 = B2	A1 = B1	A0 = B0	1	0	X	1	0	0
A3 = B3	A2 = B2	A1 = B1	A0 < B0	X	X	X	1	0	0
A3 = B3	A2 = B2	A1 < B1	X	X	X	X	1	0	0
A3 = B3	A2 < B2	X	X	X	X	X	1	0	0
A3 < B3	X	X	X	X	X	X	1	0	0

X = Don't Care

Logic 1 = High Level

Logic 0 = Low Level



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STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)							UNITS
	V _O (V)	V _{IN} (V)	V _{DD} (V)	-55	-40	+85	+125	+25			
								Min.	Typ.	Max.	
Quiescent Device Current, I _{DD} Max.	—	0,5	5	5	5	150	150	—	0,04	5	μA
	—	0,10	10	10	10	300	300	—	0,04	10	
	—	0,15	15	20	20	600	600	—	0,04	20	
	—	0,20	20	100	100	3000	3000	—	0,08	100	
Output Low (Sink) Current I _{OL} Min.	0,4	0,5	5	0,64	0,61	0,42	0,36	0,51	1	—	mA
	0,5	0,10	10	1,6	1,5	1,1	0,9	1,3	2,6	—	
	1,5	0,15	15	4,2	4	2,8	2,4	3,4	6,8	—	
Output High (Source) Current, I _{OH} Min.	4,6	0,5	5	-0,64	-0,61	-0,42	-0,36	-0,51	-1	—	mA
	2,5	0,5	5	-2	-1,8	-1,3	-1,15	-1,6	-3,2	—	
	9,5	0,10	10	-1,6	-1,5	-1,1	-0,9	-1,3	-2,6	—	
	13,5	0,15	15	-4,2	-4	-2,8	-2,4	-3,4	-6,8	—	
Output Voltage: Low-Level, V _{OL} Max.	—	0,5	5	0,05				—	0	0,05	V
	—	0,10	10	0,05				—	0	0,05	
	—	0,15	15	0,05				—	0	0,05	
Output Voltage: High-Level, V _{OH} Min.	—	0,5	5	4,95				4,95	5	—	V
	—	0,10	10	9,95				9,95	10	—	
	—	0,15	15	14,95				14,95	15	—	
Input Low Voltage V _{IL} Max.	0,5,4,5	—	5	1,5				—	—	1,5	V
	1,9	—	10	3				—	—	3	
	1,5,13,5	—	15	4				—	—	4	
Input High Voltage, V _{IH} Min.	0,5,4,5	—	5	3,5				3,5	—	—	V
	1,9	—	10	7				7	—	—	
	1,5,13,5	—	15	11				11	—	—	
Input Current I _{IN} Max.	—	0,18	18	±0,1	±0,1	±1	±1	—	±10 ⁻⁵	±0,1	μA

DYNAMIC ELECTRICAL CHARACTERISTICS

At T_A = 25°C; Input t_r, t_f = 20 ns, C_L = 50 pF, R_L = 200 kΩ

CHARACTERISTIC	TEST CONDITIONS	V _{DD} Volts	LIMITS		UNITS
			Typ.	Max.	
Propagation Delay Time: Comparing Inputs to Outputs, t _{PHL} , t _{PLH}		5	300	600	ns
		10	125	250	
		15	80	160	
Cascading Inputs to Outputs, t _{PHL} , t _{PLH}		5	200	400	ns
		10	80	160	
		15	60	120	
Transition Time, t _{THL} , t _{TLH}		5	100	200	ns
		10	50	100	
		15	40	80	
Input Capacitance, C _{IN}	Any Input		5	7,5	pF

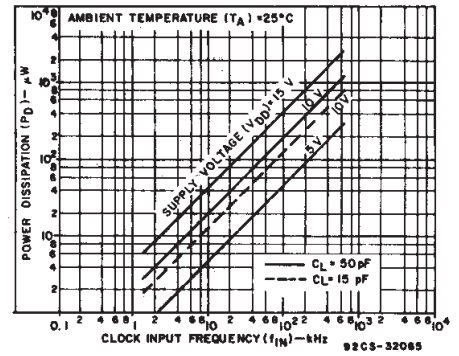


Fig. 8 — Typical dynamic power dissipation as a function of clock input frequency (see Fig. 9—dynamic power dissipation test circuit).

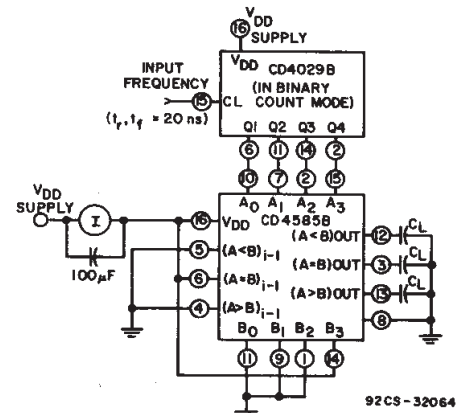


Fig. 9 — Dynamic power dissipation test circuit.

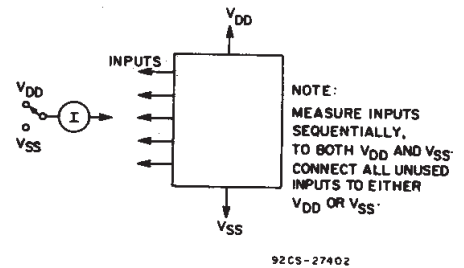


Fig. 10 — Input current test circuit.

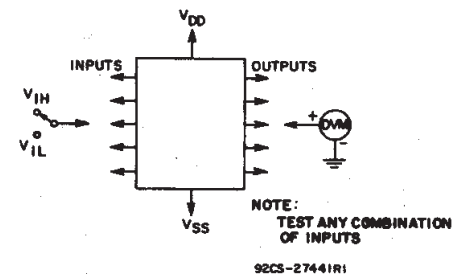


Fig. 11 — Input-voltage test circuit.

CD4585B Types

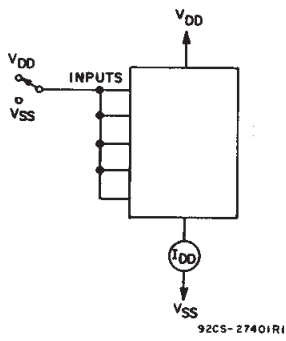
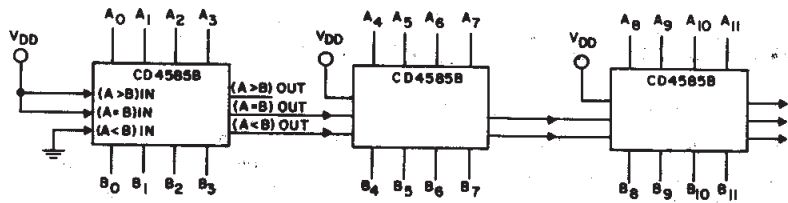


Fig. 12 — Quiescent-device-current test circuit.



$$t_p \text{ TOTAL} = t_p \text{ (COMPARE INPUTS)} + 2 \times t_p \text{ (CASCADE INPUTS)}, \text{ AT } V_{DD} = 10V$$

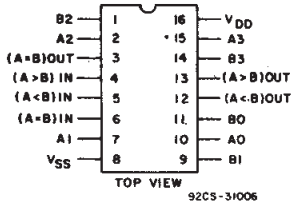
$$(3 \text{ STAGES})$$

$$= 120 + 2(80) = 280 \text{ ns (TYP.)}$$

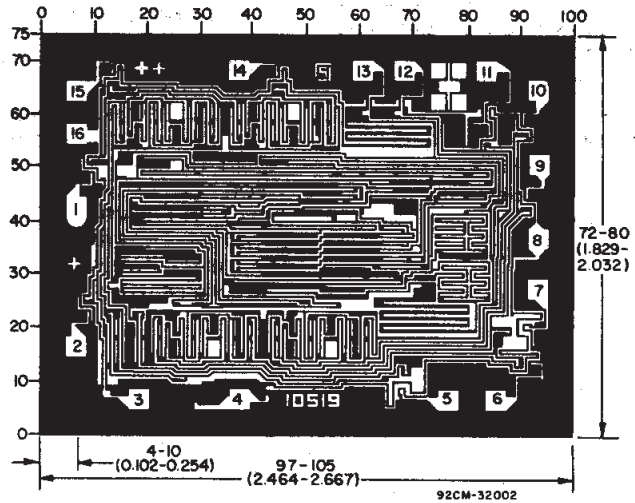
92CM-31007R1

Fig. 13 — Typical speed characteristics of a 12-bit comparator.

TERMINAL ASSIGNMENT



92CS-31006



92CM-32002

Dimensions and Pad Layout for CD4585BH

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).

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